

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/518,367	SHIGA ET AL.	
	Examiner	Art Unit	
	Tran N. Nguyen	2834	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,657,328	12-2003	Shiga et al.	310/26
*	B US-6,492,756	12-2002	Maslov et al.	310/156.12
*	C US-6,093,984	07-2000	Shiga et al.	310/26
*	D US-5,767,601	06-1998	Uchiyama, Hidekazu	310/190
*	E US-6,727,632	04-2004	Kusase, Shin	310/266
*	F US-5,920,139	07-1999	Fujiwara et al.	310/154.11
*	G US-6,396,177	05-2002	Shin et al.	310/63
*	H US-5,929,547	07-1999	Kim, Tae-duk	310/156.53
*	I US-5,962,944	10-1999	Narita et al.	310/156.53
*	J US-6,257,027	07-2001	Imai, Masahiro	68/12.12
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP2002247784A	08-2002	Japan	Ukai et al	310/156.53
O	JP2002034187A	01-2002	Japan	Ukai et al	310/156.53
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U		
	V		
	W		
	X		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.